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FORM PTO-1449	ATTY. DKT NO.	1-103-CON4	SER. NO.
	APPLICANT	MAMITSU et al.	
	FILING DATE	N v. 4, 2003	GROUP

## REFERENCE DESIGNATION

### U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>RF</i>	5,708,299	Jan. 13, 1998	Teramae et al		
<i>RF</i>	6,072,240	June 6, 2000	Kimura et al		
<i>RF</i>	5,248,853	Sep. 28, 1993	Ishikawa et al		
<i>RF</i>	5,801,445	Sep. 1, 1998	Ishihara et al		
<i>RF</i>	5,229,646	Jul. 20, 1993	Tsumura		
<i>RF</i>	4,558,345	Dec. 10, 1985	Dwyer et al		
<i>RF</i>	4,546,374	Oct. 8, 1985	Olsen et al		
<i>RF</i>	4,984,061	Jan. 8, 1991	Matsumoto		
<i>RF</i>	5,481,137	Jan 2, 1996	Harada et al.		
<i>RF</i>	4,827,082	May 2, 1989	Horiuchi et al		
<i>RF</i>	4,538,170	Aug. 27, 1985	Yerman		

### FOREIGN PATENT DOCUMENTS

#### TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>RF</i>	EP0660396	12/24/93	Europe					
<i>RF</i>	EP0450980	4/05/91	Europe					
<i>RF</i>	6-291223	10/94	JAPAN					
<i>RF</i>	3-20067	01/91	JAPAN					
<i>RF</i>	2146174	11/85	GB					

### OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>RF</i>	Takamura, "Electronic Technology", pp. 56-59 (1999-5).
<i>RF</i>	Johnson et al., "Silicon Precipitate Nodule-Induced Failures of MOSFETS", ISTFA '91 (Nov. 11-15, 1991), pp. 161-165.
EXAMINER	DATE CONSIDERED
<i>RF</i>	7/2/04

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## REFERENCE DESIGNATION

### U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>RF</i>	4,646,129	Feb. 24, 1987	Yerman et al		
<i>RF</i>	4,141,030	Feb. 20, 1979	Eisele et al		
<i>RF</i>	6,448,645	Sep. 10, 2002	Kimura		
<i>RF</i>	6,538,308	Mar. 25, 2003	Nakase		
<i>RF</i>	6,380,622	Apr. 30, 2002	Hirai		
<i>RF</i>	09/675,209	Filed Sept. 29, 2000	Suzuki		
<i>RF</i>	5,221,851	Jun. 22, 1993	Gobrecht et al.		

### FOREIGN PATENT DOCUMENTS

								TRANSLATION	
		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>RF</i>		4-249353	9/92	JAPAN					
<i>RF</i>		11-260979	09/99	JAPAN					
<i>RF</i>		4-27145	01/92	JAPAN					
<i>RF</i>		9-148492	06/97	JAPAN					
<i>RF</i>		4-12555	01/92	JAPAN					
<i>RF</i>		4-103150	04/92	JAPAN					
<i>RF</i>		60-137042	07/85	JAPAN					
<i>RF</i>		5-109919	04/93	JAPAN					
<i>RF</i>		61-166051	07/86	JAPAN					
<i>RF</i>		2-117157	05/90	JAPAN					
<i>RF</i>		63-102326	05/88	JAPAN					

### OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

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### U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>RB</i>	5,990,550	Nov. 23, 1999	Umezawa		
<i>RB</i>	5,608,610	Mar. 4, 1997	Brzezinski		
<i>RB</i>	5,396,403	Mar. 7, 1995	Patel		
<i>RB</i>	5,293,301	Mar. 8, 1994	Tanaka et al.		
<i>RB</i>	5,641,997	June 24, 1997	Ohta et al.		
<i>RB</i>	5,789,820	Aug. 4, 1998	Yamashita		

### FOREIGN PATENT DOCUMENTS

#### TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>RB</i>	60-235430	11/85	JAPAN					
<i>RB</i>	07-240432	9/95	JAPAN					
<i>RB</i>	8-45874	2/96	JAPAN					
<i>RB</i>	60-95947	05/85	JAPAN					
<i>RB</i>	61-265849	11/86	JAPAN					
<i>RB</i>	62-141751	06/87	JAPAN					
<i>RB</i>	63-096946	04/88	JAPAN					
<i>RB</i>	62-92349	4/87	JAPAN					
<i>RB</i>	62-287649	12/87	JAPAN					
<i>RB</i>	59-38734	09/84	JAPAN					
<i>RB</i>	01-228138	09/89	JAPAN					
<i>RB</i>	54-40569	03/79	JAPAN					
<i>RB</i>	61-251043	11/86	JAPAN					
<i>RB</i>	54-95183	07/79	JAPAN					

### OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

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### U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>[Signature]</i>	2002/0158333	Oct. 31, 2002	Teshima		
<i>[Signature]</i>	S/N 10/201556	July 24, 2002	Hirano et al.		
<i>[Signature]</i>	5726466	March 10, 1998	Nishitani		
<i>[Signature]</i>	4,470,063	Sep. 4, 1984	Arakawa et al.		
<i>[Signature]</i>	5,708,299	Jan. 13, 1998	Teramae et al		

### FOREIGN PATENT DOCUMENTS

#### TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>[Signature]</i>	59-031042	02/84	JAPAN					
<i>[Signature]</i>	07-038013	02/95	JAPAN					
<i>[Signature]</i>	07-273276	10/95	JAPAN					
<i>[Signature]</i>	08-191145	07/96	JAPAN					
<i>[Signature]</i>	2000-91485	03/00	JAPAN					
<i>[Signature]</i>	W098/12748	3/26/98	PCT					
<i>[Signature]</i>	JP-A-5-283562 *	10/29/93	JAPAN				X	
<i>[Signature]</i>	JP-A-6-349987 *	12/22/94	JAPAN				X	
<i>[Signature]</i>	JP-A-7-45765 *	2/14/95	JAPAN				X	
<i>[Signature]</i>	JP-A-11-186469 *	7/9/99	JAPAN				X	
<i>[Signature]</i>	JP-A-2000-31351 *	1/28/00	JAPAN				X	
<i>[Signature]</i>	JP-A-2001-118961 *	4/27/01	JAPAN				X	

### OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>[Signature]</i>	
DATE CONSIDERED	8/2/04	